Approved by:

Checked by:

Issued by:

SPECIFICATION

MODEL: HDF434.42M(F11)

SHUOLDER ELECTRONICS LIMITED

1.Package





2.Performance

2.1 Absolute Maximum Ratings

Rating	Value	Units	
Incident RF Power	+13	dBm	
Case Temperature	-40 to +85	°C	
DC Voltage Between Any Two Pins (Observe ESD Precautions)	±30	VDC	

2.2 Electrical Characteristics

R	eference temperature: T _A	= 25	з°С		
Terminating source impedance: $Z_s =$		50 Ω and matching network			
Terminating load impedance: $Z_{L} = 50 \Omega$ and matching network					
	Characteristic	Min.	Тур.		
f _c (ce	Center Frequency nter frequency between 3dB points)		434.42		MHz
	Insertion Loss IL		3.0	5.5	dB
	3dB Passband BW ₃		±300		kHz
	3 dB Reject Band BW ₃			± 500	kHz
Rejection	at f _c -21.4MHz(Image)	40	50		dB
	at f _c -10.7MHz(LO)	15	30		
	Ultimate		80		
Temperature	Operating Case Temperature Tc	-35		+85	°C
	Turnover Temperature To	15	25	40	
	Turnover Frequency fo		fc		MHz
	Frequency Temperature Coefficient FTC		0.032		ppm/°C
Frequency Ag	ing Absolute Value during the First Year		10		ppm/yr

CAUTION: Electrostatic Sensitive Device. Observe precautions for handling!

3. Matching network to $50 \,\Omega$ (element values depend on pcb layout and equivalent circuit)



Cp1 =10pF, Ls2 =43nH*, Ls3 =43nH*, Cp4 =10pF

Ls2 = Ls3 = 6 turns of 0.51mm insulated Copper, 2.5mm ID.



4. Typical Frequency Response

5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in table 1.

5-2 Low temperature exposure

Subject the device to -20° C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in table 1.

5-3 Temperature cycling

Subject the device to a low temperature of -40° C for 30 minutes. Following by a high temperature of $+80^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in table 1.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at 260°C $\pm 10^{\circ}$ C for 10 ± 1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in table 1.

5-5 Solderability

Subject the device terminals into the solder bath at 245° C for 5s, More

than 95% area of the terminals must be covered with new solder. It shall meet the specifications in table 1.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in table 1.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in table 1.

- 5-8 Lead fatigue
 - 5-8-1 Pulling test

Weight along with the direction of lead without an shock 1kg. The device shall satisfy all the initial Characteristics.

5-8-2 Bending test

Lead shall be subject to withstand against 90° C bending with 450g weight in the direction of thickness. This operation shall be done toward both direction. The device shall show no evidence of damage and shall satisfy all the initial electrical characteristics.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be solded. Please avoid soldering another part of component.